

Main section Probe Station System & Assesories

Sub section :- Probe Station System

1) A Series Full Automatic Probe Station



Product Overview

A series is SEMISHARE years carefully developed a production automatic high and low temperature probe, the probe station has high test precision and super fast test speed, with automatic up-down material, automatic wafer alignment, automatic wafer center, automatic test diesize, etc, has the identification function of wafer ID at the same time, can be a single point test can also be continuous testing, test software feature-rich, heavily for the enterprise to gain test speed, greatly improving the productivity and efficiency.

Basic Information

Product number	A8, A12, A12S	working environment	Open type
electricity demand	220 V, 50/60Hz	Control method	Full-Automatic
Product Size	A8((1124*1158*955mm) ; A12(1467*1768*1400mm); A12S(1467*1768*1400mm)	equipment weight	1.2T, 2T, 2.2T

Application direction

Wafer testing of various kinds of devices Wafer and other Wafer performed RF testing and other characteristics analysis of I-V C-V optical signal RF 1/ F noise, etc.

Technical characteristics